



Software solutions  
for optimizing micro  
& nano fabrication



# Australia Workshop 2026 Advanced SEM Metrology



**Time:** Wednesday, February 4<sup>th</sup>, 2026  
9:30 – 12:30 (AEDT)

**Location:** [Hilton Sydney](#)

GenISys' well-known software package **ProSEM** offers advanced image analysis for monitoring micro and nanostructures, while **InSPEC** is a new upgrade kit to convert an analytical SEM into a flexible and integrated solution for automated SEM metrology and inspection.

This workshop will explore the capabilities for SEM metrology to support lithography and nanofabrication.

Registration for our Metrology Workshop, which is free of charge, can be done

- by sending an Email to **Nit Taksatorn**: [taksatorn@genisys-gmbh.com](mailto:taksatorn@genisys-gmbh.com)
- on our website providing also further the details: [Australia Metrology Workshop 2026](#).

Feel free to share this information with colleagues who may wish to join as well.

We are looking forward to having an interesting and inspiring workshop with you!

Thank you,

**The GenISys Team**

| Metrology Workshop 2026 on InSPEC & ProSEM |  |              |
|--|--|--------------|
| Wednesday, February 4 <sup>th</sup> , 2026 |  |              |
| Nit Taksatorn<br>GenISys                   | <b>Arrival</b>   | <b>09:30</b> |
| Nit Taksatorn<br>GenISys                   | GenISys Company Update   | 10:00        |
| Sven Bauerdick<br>GenISys                  | <b>ProSEM</b> Update and Roadmap<br>Presentation and Discussion                              | 10:15        |
| Sven Bauerdick<br>GenISys                  | <b>InSPEC</b> Introduction, Capabilities, and Applications<br>Presentation and Demonstration | 10:45        |
|  | <b>Buffet Lunch</b>  | <b>12:30</b> |

Morning tea and coffee will be provided, followed by a buffet lunch.

